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Optical circuit boards - Part 2-4: Tests - Optical transmission test for optical circuit boards without input/output fibres

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NORME FUROPÉENNE **EUROPÄISCHE NORM**

August 2013

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English version

Optical circuit boards -Basic test and measurement procedures -Part 2-4: Optical transmission test for optical circuit boards without input/output fibres

(IEC 62496-2-4:2013)

Cartes à circuits optiques -

Procédures fondamentales d'essais et de mesures -

Partie 2-4: Essai de transmission optique des cartes à circuits optiques sans fibres

d'entrée/sortie (CEI 62496-2-4:2013) Teh STANDARD

Optische Leiterplatten -Grundlegende Prüf- und Messverfahren -

Teil 2-4: Optische Übertragungsprüfung für optische Leiterplatten ohne Eingangs-

/Ausgangsfasern

(IEC 62496-2-4:2013)

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Foreword

The text of document 86/449/FDIS, future edition 1 of IEC 62496-2-4, prepared by IEC TC 86 "Fibre optics" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62496-2-4:2013.

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In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 62496-2-1

NOTE Harmonised as EN 62496-2-1.

IEC 60793-2

NOTE Harmonised as EN 60793-2.

IEC 62496

NOTE Harmonised in EN 62496 series (not modified).

Annex ZA

(normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

PublicationYearTitleEN/HDYearIEC 60068-1-Environmental testing -
Part 1: General and guidanceEN 60068-1-

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NORME INTERNATIONALE



Optical circuit boards—Basic test and measurement procedures —
Part 2-4: Optical transmission test for optical circuit boards without input/output fibres

SIST EN 62496-2-4:2013

Cartes à circuits optiques — Procédures fondamentales d'essais et de mesures – Partie 2-4: Essai de transmission optique des cartes à circuits optiques sans fibres d'entrée/sortie

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

OPTICAL CIRCUIT BOARDS – BASIC TEST AND MEASUREMENT PROCEDURES –

Part 2-4: Optical transmission test for optical circuit boards without input/output fibres

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International Standard IEC 62496-2-4 has been prepared by IEC technical committee 86: Fibre optics.

The text of this standard is based on the following documents:

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Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

-5-

A list of all parts of the IEC 62496 series, published under the general title *Optical circuit boards – Basic test and measurement procedures*, can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

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